

SOPHISTICATED ANALYTICAL INSTRUMENT FACILITY(SAIF)

(Sponsored by Department of Science & Technology, Government of India)

No. SAIF/NEHU/SHG/EOI/2026- 1264

Date : 15/10/26

NOTIFICATION

Expression of Interest (EOI) for Repair and Restoration of Scientific Instruments at SAIF, NEHU

Date: 13.10.2026

The Sophisticated Analytical Instrument Facility (SAIF), North-Eastern Hill University (NEHU), Shillong, invites **Expressions of Interest (EOI)** from reputed Original Equipment Manufacturers (OEMs), authorized service providers, qualified technical agencies, and experienced firms and experienced independent service providers possessing the necessary technical expertise and experience in the diagnosis, repair, servicing, and restoration of sophisticated scientific instruments installed at SAIF, NEHU.

The EOI is invited for the repair and restoration of the following instruments:

Sl. No.	Name of Instrument	Make/Model	Nature of Repair Required
1.	Scanning Electron Microscope (SEM)	JEOL JSM-6360	Diagnosis and repair of power supply/control unit, SMPS, filament heating and communication-related faults.
2.	Microscope with Image analyser	Leica DMRX Q600	Power supply and faulty lens.
3.	Microwave Digester	Perkin Elmer, Multiwave 3000	Program cannot be executed.
4.	LC-MS	Waters ZQ 4000	Mass is not communicating.

1. Scope of Work

The scope of work shall include:

1. Preliminary technical assessment and identification of faults in the respective instruments.
2. Inspection and diagnosis of defective components, electronic circuits, control systems, power supplies and associated accessories, wherever applicable.
3. Submission of a detailed technical report indicating the nature of faults, feasibility of repair, required replacement components and estimated expenditure.
4. Repair, replacement, servicing and restoration of defective components, as approved by the University.
5. Functional testing, calibration wherever applicable, and demonstration of satisfactory performance following repair.
6. Provision of appropriate warranty or service support for the repairs undertaken.

2. Eligibility Criteria

Interested firms/agencies should preferably possess:

1. Demonstrable experience in repairing and maintaining sophisticated analytical and scientific instruments.
2. Qualified technical personnel with relevant expertise.
3. Necessary diagnostic tools, technical facilities and access to compatible spare parts.
4. Previous experience in servicing similar instruments at universities, research institutions, government laboratories or other recognized organizations.
5. Valid business registration and applicable statutory documents.

OEM authorization may be furnished wherever available. However, technically competent independent service providers with proven experience may also submit their EOI.

3. Submission of Expression of Interest

Interested parties are requested to submit the following information:

1. Profile of the firm/agency, including contact details.
2. Details of relevant technical expertise and previous experience.
3. List of similar instruments repaired or serviced, preferably with supporting documents.
4. Preliminary assessment of repair feasibility, wherever possible.
5. Availability of spare parts and technical support.
6. Indicative cost of inspection, diagnosis and repair, if ascertainable.
7. Expected timeframe for inspection and completion of repairs.

4. Last Date for Submission

The last date for submission of the Expression of Interest is 26 October 2026.

Interested parties may submit their EOI through email or in hard copy to the following address:

The Head

Sophisticated Analytical Instrument Facility (SAIF)
North-Eastern Hill University
Shillong – 793022, Meghalaya, India

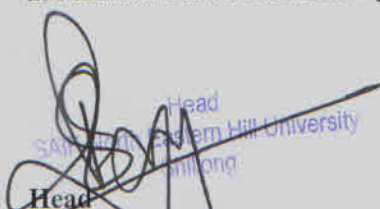
Email: [hodsaiif@nehu.ac.in and Cc to offsaif@nehu.ac.in]

Subject of Email: Expression of Interest for Repair of Scientific Instruments at SAIF-NEHU

5. General Terms and Conditions

1. Submission of an EOI shall not constitute any commitment by NEHU to award repair or maintenance work.
2. The University reserves the right to shortlist technically competent firms/agencies and seek further technical or financial proposals.
3. Interested parties may be invited to inspect the instruments at SAIF, NEHU, subject to prior permission.
4. Any inspection charges, if applicable, must be clearly indicated in advance and shall be subject to prior approval.
5. Repair work shall be undertaken only after obtaining necessary administrative and financial approvals from the competent authority.
6. NEHU reserves the right to accept or reject any or all EOIs, or cancel the process, without assigning any reason.

Interested OEMs, service providers and technically competent agencies are encouraged to participate in this initiative aimed at restoring essential scientific research facilities at NEHU.


Head
Sophisticated Analytical Instrument Facility (SAIF)
North-Eastern Hill University
Shillong – 793022